

Contents

1.	Introd	uction	P.	4
2.	Featur	res	P.	4
3.	Block	Diagram	P.	5
4.	Pin Co	onnections	P.	6
5.	Signal	Description	P.	7
6.	Functi	ions	P.	8
	6. 1	Common Memory	P.	8
	6. 2	Common Memory	P.	9
	6. 3	Function Table		9
	6.4	Enhancement Functions	P.	10
	6.5	SmartVoltage	P.	11
7.	Card I	nformation Structure (CIS)	P.	12
8.	Card (Control	P.	14
	8.1	Bus Operations	P.	14
	8. 2	Standby	P.	15
	8.3	Bus Operations	P.	15
	8.4	Reset	P.	15
	8.5	Read Identifier Codes Operation	P.	15
	8.6	Status Register		16
	8. 7	CUI Writes	P.	17
	8.8	Write Protect Switch		17
9.	Comp	onent Management Register (CMR)	P.	17
10.	Comm	and Definitions	P.	20
1	10. 1	Read Array Command	P.	21
	10. 2	Read Identifier Codes Command	P.	21
	10, 3	Read Status Register Command	P.	21
	10. 4	Clear Status Register Command	P.	22
	10. 5	Block Erase Command	P.	22
	10. 6	Word/Byte Write Command	P.	22
	10. 7	Block Erase Suspend Command	P.	23
	10. 8	Word/Byte Write Suspend Command	P.	23
	10. 9	Set Block Lock-Bit Command	P.	23
	10. 10) Set Master Lock-Bit Command	P.	24

2

10. 11 Clear Block Lock-Bits Command	P.	24
10. 12 Automated Word Write Flowchart	P.	25
10. 13 Automated Block Erase Flowchart	P.	26
11. Electrical Specifications	P.	27
11. 1 Absolute Maximum Ratings	P .	27
11. 2 Recommended Operating Conditions	P.	27
11. 3 Capacitance	P.	27
11. 4 AC Input/Output Test Conditions	P.	27
12. DC Characteristics	Р.	-28
13. AC Characteristics	P.	30
13. 1 Common and Attribute Memory Read Operations		
13. 2 Command Write Operations : Common Memory	P.	32
13. 3 Power-Up/Power Down		
14. Specification Changes	P.	39
 14. Specification Changes	P.	39
16. External Diagrams	P.	40

•

1. Introduction

This datasheet is for SHARP's ID242 series flash memory card. This datasheet provides all AC and DC characteristics (including timing waveforms) and a convenient reference for the device command set and the card's integrated registers(including the LH28F008SC's status registers). This datasheet provides description of the methods which are very helpful for customer to use the card.

2. Features

2.1 **Type**

Flash Memory Card

2.2 Overview

	ID242Dxx	ID242Exx	ID242Gxx					
Common Memory Capacity	2M words × 8bits 1Mwords × 16bits	4M words × 8bits 2M words × 16bits	814 words × 8bits 4M words × 16bits					
Attribute Memory Capasity	2KBytes							
Supply Voltage	Smart Voltage							
Access time	150ns(@Vcc=\$v) 250ns(@Vcc=3.3w)							
Erase Unit	64K word blocks							
Program/Erase Cycles	- 100,000cycles/Block							
External Dimensions	54.0 × 85.6 × 3.3mm PCMCIA Type 1							

2.3	Interface	Parallel I/O Interface
2.4	Function Table	See Function Table in page. 9
2.5	Pin Connections	See Pin Connections in page. 6
2.6	Type of Connector	Conforms to PCMCIA PC Card Standard 95 Card Use Connector
		(Card connector: JC20-J68S-NB3 JAE or FCN-568J068-G/0 Fujitsu)
2.7	Operating Temperature	0 to 60°C
2.8	Storage Temperature	-20 to 65°C
20	Not designed for rated radiation	on hardened

2.9 Not designed for rated radiation hardened.

æ.



5

4. Pin Connections

 Table 1.
 Pin Connections

PIN No.	SIGNAL	I/O	FUNCTION	ACTIVE	PIN No.	SIGNAL	I/O	FUNCTION	ACTIVE
1	GND		Ground		35	GND		Ground	
2	D ₃	I/O	Data Bit 3		36	CD ₁ #	0	Card Detect 1	LOW
3	D ₄	I/O	Data Bit 4		37	D ₁₁	I/O	Data Bit 11	
4	D ₅	I/O	Data Bit 5		38	D ₁₂	I/O	Data Bit 12	
5	D ₆	I/O	Data Bit 6		39	D ₁₃	I/O	Data Bit 13	
6	D ₇	I/O	Data Bit 7		40	D ₁₄	I/O	Data Bit 14	
7	CE ₁ #	Ι	Card Enable 1	LOW	41	D ₁₅	I/O	Data Bit 15	
8	A ₁₀	Ι	Address Bit 10		42	CE ₂ #	Ĩ	Card Enable 2	LOW
9	OE#	Ι	Output Enable	LOW	43	VS ₁ #	0	Voltage Sense 1	LOW
10	A ₁₁	Ι	Address Bit 11		44	RFU		Reserved	
11	A ₉	Ι	Address Bit 9		45	RFU		Reserved	
12	A ₈	I	Address Bit 8		46	A ₁₇	I	Address Bit 17	
13	A ₁₃	Ι	Address Bit 13		47	A ₁₈	I	Address Bit 18	
14	A ₁₄	Ι	Address Bit 14		48	A _{ia}	Ι	Address Bit 19	
15	WE#	I	Write Enable	LOW	49	A ₂₀	I	Address Bit 20	
16	RDY/BSY#	0	Ready Busy	LOW	50	A ₂₁	I	Address Bit 21	
17	V _{cc}		Supply Voltage		51	V _{cc}		Supply Voltage	
18	V _{ppi}		Program Voltage		52	V _{PP2}		Program Voltage	
19	A ₁₆	Ι	Address Bit 16	Ø	53	A ₂₂	Ι	Address Bit 22	
20	A ₁₅	Ι	Address Bit 15		54	A ₂₃	I	Address Bit 23	
21	A ₁₂	Ι	Address Bit 12		55	A ₂₄	Ι	Address Bit 24	
22	A ₇	J	Address Bit 7		56	A_25	I	Address Bit 25	
	A ₆	I	Address Bit 6		57	VS ₂ #	0	Voltage Sense 2	N.C.
	A ₅	I	Address Bit 5		58	RESET	Ι	Reset	HIGH
25	A ₄	I	Address Bit 4		59	RFU		Reserved	
26	A,	I	Address Bit 3		60	RFU		Reserved	
27	A ₂	Ι	Address Bit 2		61	REG#	Ι	Atribute Memory Select	
28	A ₁	I	Address Bit 1		62	BVD ₂	0	Battery Boltage Detect 2	
29	A ₀	Ι	Address Bit 0		63	BVD ₁	0	Battery Boltage Detect 1	
30	D ₀	I/O	Data Bit 0		64	D ₈	I/O	Data Bit 8	
31	D	I/O	Data Bit 1		65	D,	I/O	Data Bit 9	
32	D ₂	I/O	Data Bit 2		66	D ₁₀	I/O	Data Bit 10	
33	WP	0	Write Protect	HIGH	67	CD ₂ #	0	Card Detect 2	LOW
34	GND		Ground		68	GND		Ground	

.

5. Signal Description

Table 2. Signal Description

Symbol	1/0	Electrical Interface	Function
Symbol	10		
A ₀ -A ₂₅	I	Pull-down (250kΩ@Vcc=5v)	ADDRESS INPUTS: Address A0 through A22 are address bus lines which enable direc addressing of up to 8MB of memory on the card. Signal A0 is not used in word access mode. A23 through A25 are open. The system should NOT try to access memory beyond the card's density, because the upper addresses are not decoded.
D ₀ -D ₁₅	I/O	Pull-down (250kΩ@Vcc=5v)	DATA INPUT/OUTPUT: D0 through D15 constitute the bi-directional data bus. D15 is the mos significant bit.
CE ₁ #,CE ₂ #	I	Pull-up (250kΩ@Vcc=5v)	CARD ENABLE 1 & 2: CE1# enables even byte, CE2# enables odd byte.
OE#	I	Pull-up $(250k \Omega @Vcc=5v)$	OUTPUT ENABLE: Active low signal gating read data from the memory card.
WE#	I	Pull-up (250kΩ@Vcc=5v)	WRITE ENABLE: Active low signal gating write data to the memory card.
RDY/BSY#	0		READY/BUSY OUTPUT: Indicates status of internally timed erase or write activities. ID24 series has two types of Ready/Busy output mode; PCMCIA mode and High-Performance mode. In PCMCIA mode, a high output indicates the memory card is ready to accept accesses. A low output indicates that a device in the memory card is busy. In High-Performance mode, the card outputs low when the card is in default state. A high output indicates at least one of flash memory devices in the card comes to be ready to accept accesses.
CD ₁ #, CD ₂ #	0	Pu il -down θΩ	CARD DETECT 1 & 2: These signals provide for card insertion detection. The signals are connected to ground internally on the memory card, and will be forced low whenever a card is placed in the socket. The host socket interface circuitry shall supply 10K or larger pull-up resistors on these signations.
WP	0	Low:Pull-down 0Ω High:Pull-up 100kΩ	WRITE PROTECT: Write Protect reflects the status of the Write Protect switch on th memory card. WP set to high = write protected.
V V			WRITE/ERASE POWER SUPPLY 1 & 2:
V _{PP1} , V _{PP2}			
)		CARD POWER SUPPLY:
V _{cc}	, 		CARD POWER SUPPLY: GROUND:
V _{cc} GND REG#	I	Pull-up (250kΩ@Vcc=5v)	
V _{cc} GND	I	-	GROUND: REGISTER SELECT:
V _{cc} GND REG# RESET		(250kΩ@Vcc=5v) Pull-up	GROUND: REGISTER SELECT: Provides access to attribute memory when REG# is low. RESET: Active high signal for placing card in Power-On Default State. BATTERY VOLTAGE DETECT 1 & 2:
V _{cc} GND REG#	I	$(250k\Omega@Vcc=5v)$ Pull-up $(250k\Omega@Vcc=5v)$	GROUND: REGISTER SELECT: Provides access to attribute memory when REG# is low. RESET: Active high signal for placing card in Power-On Default State.

•

.

6. Functions

6.1 Common Memory

6.1.1 Common Memory Architecture

Figure 2 shows common memory architecture of ID242 series flash memory card. Device pair is consisted of two pieces of 8Mbit flash memory devices. Each device has 16 distinct, individually erasable and lockable blocks. All blocks are divided into odd bytes and even bytes.



Figure 2. Common Memory Architecture

Each device pair and block is selected by address bits. Table 3 shows definitions of address bits.

Table 3. Address Diffinitions

A	Select Even/Odd byte in the byte access mode.
A ₁₆ -A ₁	Select address in the block.
A ₃₀ A ₁₇	Select a block.
A ₂₅ A ₂₀	Select a device pair.

6.1.2 Erase

Erase is executed one block at a time. Erasable block size is 64K bytes in byte access mode and 128K bytes in word access mode.

6.1.3 Address Decoding

The higher address area of ID242 series flash memory card which goes beyond common memory area is not decoded in common memory access. It means that the system will access to random memory address of the memory card even if system will try to access to the memory address which exceeds memory capacity of the card. Please do not access to the memory address which goes beyond memory capacity of the card.

As an enhanced function, the memory card enables to output invalid data (either of 0000h or FFFFh) when system will access to the memory address which exceeds memory capacity of the card. Please contact our sales & marketing people to find concrete way of setting.

6.2 Attribute Memory

Figure 3 shows attribute memory architecture of ID242 series flash memory card. Attribute memory is contained within the Card Control Logic. Attribute memory contains the Card Information Structure (CIS) and Component Management Registers (CMRs). The CIS contains tuple information and is located at even byte addresses beginning with address 0000h (Please refer to section 7). The standard CIS of ID242 series flash memory card is hardwired and is for read only. As an enhanced function, the hardwired CIS area is switchable to EEPROM so that customer can program required CIS. Please contact our sales & marketing people to find concrete way of setting. The CMRs are located at even byte addresses beginning with address 4000h (Please refer to section 9).



6.3 Function Table

6.3.1 Common Memory Access

Table 4 Common Memory Access

Figure 3.	Attribute	Memory	Map
-----------	-----------	--------	-----

			1990 - 1990 - 1 990 - 19900 - 1990 - 19900 - 19900 - 19900 - 1990 - 1990 - 1990 - 1990 - 199					
Mode	REG#	CE ₂ #	CE ₁ #	A ₀	OE#	WE#	D _{15~8}	D _{7~0}
Stand-by	X	H	H	x	X	X	High-Z	High-Z
Byte Read	Н	Н		L	L	H	High-Z	Even
Byte Read	Н	H	L	н	L	Н	High-Z	Odd
Word Read	H	L.	Ľ	X	L	Н	Odd	Even
Odd Byte Read	Н	L	Н	X	L	Н	Odd	High-Z
Byte Write	Н	н	L	L	Н	L	Don't care	Even
	Н	н	L	Н	н	L	Don't care	Odd
Word Write	H	L	L	X	Н	L	Odd	Even
Odd Byte write	Н	L	Н	X	Н	L	Odd	Don't care

Attribute Memory Access 6.3.2

Table 5. Attribute Memory Access

Mode	REG#	CE ₂ #	CE ₁ #	A ₀	OE#	WE#	D ₁₅₋₈	D ₇₋₀
Stand-by	X	Н	Н	X	x	X	High-Z	High-Z
Byte Read	L	Н	L	L	L	Н	High-Z	Even .
byte Reau	L	Н	L	Н	L	н	High-Z	XXX
Word Read	L	L	L	X	L	Н	XXX	Even
Odd Byte Read	L	L	Н	X	L	Н	XXX	High-Z
Byte Write	L	Н	L	L	Н	L	Don't care	Even
byte white	L	Н	L	Н	Н	L	Don't care	Don't care
Word Write	L	L	L	X	н	L	Don't care	Even
Odd Byte write	L	L	Н	X	Н	L	Don't care	Don't care

XXX: Output data is invalid.

The standard CIS is for read only. Write operation is only for CMRs and CIS on EEPROM.

6.4 Enhancement Functions

ID242 series flash memory card contains enhanced control functions. By taking advantage of these enhancement functions, this card provides innovative capabilities, low-power operation and very high read/write performance. These enhancement functions are achieved by CMRs.(Please refer to section 9)

Table 6.	Enhancement	Functions
----------	-------------	-----------

Enhancement Functions	Function Preview					
Soft Reset	Initiates internal automation of the memory card by seftware reset.					
Sleep Control	Puts specified device pair(s) in deep power-down mode.					
Ready/Busy Monitor	Indicates the RDY/BSY# status of each flash memory device to Ready/Busy Status Register.					
Ready/Busy Mask	Masks RDY/BSY# status of each flash memory device.					
Ready/Busy Mode	Select RDY/BSY# output mode which PCMCIA mode or High-Performance mode.					
Software Write Protect	Executes write protect by sofware control, without Write Protect Switch.					
Soket and Copy Entry	If the similar cards installed in a system, the system can distinguish each card by this function.					

6. 4. 1 Soft Reset

The card become the reset state by setting the SRESET bit of the Configuration Option Register to "1". It is a similar function to hardware reset by the card's RESET without the SRESET bit status. The SRESET bit must be cleared("0") to enable access to the card

6. 4. 2 Sleep Control

Writing "1" to the PWDN bit of the Configuration Status Register puts selected device pairs by the Sleep Control Register into the deep power-down mode. It means keeping down the stand-by current.

6.4.3 Ready/Busy Monitor

The Ready/Busy Status Register indicates the RDY/BSY# status of each device. It means that the system can confirm the RDY/BSY# status of each device when the card's RDY/BSY# is in the High-Performance mode, the device's RDY/BSY# is masked or the card is in other mode.

6. 4. 4 Ready/Busy Mask

With setting the appropriate bits of the Ready/Busy Mask Register to "1", the corresponding device's RDY/BSY# signals are masked for card's RDY/BSY# output.

6. 4. 5 Ready/Busy Mode

ID242 series has two types of Ready/Busy output mode; PCMCIA mode and High-Performance mode. In PCMCIA mode, a high output indicates the memory card is ready to accept accesses. A low output indicates that a device in the memory card is busy. In High-Performance mode, the card outputs low when the card is in default state. A high output indicates at least one of flash memory devices in the card comes to be ready to accept

accesses. The system must clear the RACK bit of the Rady/Busy Mode Register after receiving ready status to prepare for next device's ready transition.



6. 4. 6 Software Write Protect

ID242 series flash memory card can provide Common Memory CIS (CMCIS) with first block (64Kwords in word access mode or 128KBytes in byte access mode) of the common memory. The Write Protection Register can protect the common memory or CMCIS by sofware. By setting the CMWP bit of Write Protection Register to "1", the common memory without the CMCIS area is protected from write operation. And by setting the CISWP bit to "1", the CMCIS area is protected from write operation. Software write protection is available when the write protect switch of the card is located writable position.

6. 4. 7 Socket and Copy Entry

If the similar cards installed in a system, the system can distinguish these cards by writing the Socket Number and Copy Number in the Socket and Copy Register of each card (Please refer to section 9). The Socket Number should be written in D0-D3 of Socket and Copy Register. This field indicates to the card that it is located in the n'th socket. The Copy Number should be written in D4-D6 of Socket and Copy Register. This field indicates to the card that it is located in the n'th card that it is n'th copy of the card installed in the system which is identically configured. PC cards which indicate in their CIS that they support more than one copy of identically configured card, should have a copy number (0 to MAX twin cards, MAX=n-1) written back to the Socket and Copy Register.

6.5 SmartVoltage

SmartVoltage technology provides a choice of VCC and VPP combinations as shown in Table 7. VPP is converted to 12V automatically in each common memory device. For correct conversion, VPP must be provided VPP1, VPP2 or VPP3 from the system (Please refer to Section 12). Giving the higher VPP voltage provides the higher performance, for example, reduce the write/erase operation current or shorten the write/erase time.

Table 7. SmartVoltage

V _{cc}	V _{pp}
3.3V	3.3V, 5V, 12V
5V	5V, 12V

7. Card Information Structure (CIS)

The CIS is contained within attribute memory (Please refer to section 6.2). Table 8 shows standard CIS tuples, but it is for read only. As an enhanced function, the hardwired CIS area is switchable to EEPROM so that customer can program required CIS. Please contact our sales & marketing people to find concrete way of setting.

Address	Value	Description	
00h	01h	Device Info (Common Memory)	1
02h	04h	Tuple Link	┥┝─
04h	57h	Flash Memory	┥┝╴
06h	22h	Access Time 150ns	┨┝─
08h	06h 0Eh 1Eh	Capacity 2MB 4MB 8MB	
0Ah	FFh	End of Tuple	1
0Ch	1Ch	Device Info (Common Memory Other Conditions)	
0Eh	05h	Tuple Link	1
10h	02h	Conditions 3Vce	1 [
12h	57h	Flash Memory	1 [
14h	32h	Access Time 250ns	1 [
16h	06h OEh 1Eb	Capacity 2MB 4MB 8MB	
18h	F Fh	End of Tuple	
1Ah	17h	Device Info ID (Attribute Memory)	
1Ch	04h	Tuple Link	
1Eh	1Fh	ROM	
20h	2Ah	Access Time 200ns	
22h	01h	Capacity 2KB	
24h	FFh	End of Tuple	
26h	1Dh	Device Info ID (Attribute Memory)	
28h	05h	Tuple Link	
2Ah	02h	Conditions 3Vcc	
2Ch	17h	ROM	

Table 8. Standard CIS



éli na

Address	Value	Description		Address	Value	Description
6Ah	50h	Р		BEh	02h	Index
6Ch	20h	SPACE		C0h	02h	Vcc & Vpp
6Eh	43h	С		C2h	79h	Parameter Selection
70h	4Fh	0		C4h	55h	Vcc Voltage 5V
72h	52h	R		C6h	0Ch	Icc Static 1.2mA
74h	50h	Р		C8h	06h	Icc Average 100mA
76h	4Fh	0		CAh	06h	Icc Peak 100mA
78h	52h	R		CCh	23h	Icc Powerdown 50 _µ A
7Ah	41h	Α		CEh	79h	Parameter Selection
7Ch	54h	Т		D0h	8Eh	Vpp Voltage 12V
7Eh	49h	I		D2h	7Dh	NCOK
80h	4Fh	0		D4h	1Bh	Ipp Static 150 _µ A
82h	4Eh	N		D6h	35h	Ipp Average 30mA
84h	00h	END TEXT		D8h	35h	Ipp Peak 30mA
86h	FFh	End of Tuple		DAh	52h	Ipp Powerdown 50 _µ A
88h	1 Ah	Configuration Info		DCh	1 B h	Configuration Table Entry 3
8Ah	05h	Tuple Link		DEh	11h	Tuple Link
8Ch	01h	2 Bytes Field		EOh	03h	Index
8Eh	06h	Last Index of Configuration Table	N N	E2h	02h	Vcc & Vpp
90h	00h	CMRs Base Adress	٠.	» E4h	79h	Parameter Selection
92h	40h	CMRs Base Adress		E6h	B5h	
94h	0Bh	CMR Mask		E8h	1Eh	Vcc Voltage 3.3V
96h	00h	Null		EAh	0Ch	Icc Static 1.2mA
98h	1Bh	Configuration Table Entry 1		ECh	7Dh	Icc Average 90mA
9Ah	0Fh	Tuple Link		EEh	7Dh	Icc Peak 90mA
9Ch	01h	Index		F0h	1Bh	Icc Powerdown 150 _µ A
9Eh	02h	Vcc & Vpp		F2h	79h	Parameter Selection
A0h	79h	Parameter Selection		F4h	B5h	ττ ττ 1. ο οττ
A2h	55 h	Vce Voltage 5V		F6h	9Eh	Vpp Voltage 3.3V
A4h	ØCh	Icc Static 1.2mA		F8h	7Dh	NC OK
A6h	06h	Icc Average 100mA		FAh	1Bh	Ipp Static 150 _µ A
A8h	06h	Icc Peak 100mA		FCh	75h	Ipp Average 80mA
AAh	23h	Icc Powerdown 50 _µ A		FEh	75h	Ipp Peak 80mA
ACh	79h	Parameter Selection		100h	52h	Ipp Powerdown 50 _µ A
AEh	D5h	Vpp Voltage 5V		102h	1Bh	Configuration Table Entry 4
BOh	7Dh	NC OK		104h	10h	Tuple Link
B2h	1Bh	Ipp Static 150 _µ A		106h	04h	Index
B4h	75h	Ipp Average 80mA	ļ	108h	02h	Vcc & Vpp
B6h	75h	Ipp Peak 80mA		10Ah	79h	Parameter Selection
B8h	52h	Ipp Powerdown 50 _µ A		10Ch	B5h	XI XI-H 2 2XI
BAh	1Bh	Configuration Table Entry 2	ł	10Eh	1Eh	Vcc Voltage 3.3V
BCh	0Fh	Tuple Link	ľ	110h	0Ch	Icc Static 1.2mA

Table 8. Standard CIS (Continued)

		Table 6. Stand	uaru		(Illueu)	
Address	Value	Description] [Address	Value	Description
112h	7Dh	Icc Average 90mA	1 [13Ah	20h	Manufacturer ID
114h	7Dh	Icc Peak 90mA	1 [13Ch	04h	Tuple Link
116h	1Bh	Icc Powerdown 150 _µ A	1 [13Eh	B0h	Manufacturer Code
118h	79h	Parameter Selection	1 [140h	00h	
11Ah	8Eh	Vpp Voltage 12V	1 [Manufacturer Info:
11Ch	7Dh	NC OK	11	142h	06h 07h	2MB 4MB
11Eh	1Bh	Ipp Static 150 _µ A]		07h 09h	8MB
120h	35h	Ipp Average 30mA]	144h	33h	Manufacturer Info: DVO
122h	35h	Ipp Peak 30mA]	146h	21h	Function Identification
124h	52h	Ipp Powerdown 50 _µ A]	148h	02h	Tuple Link
126h	00h	Null]	14Ah	01h	Function: MEMORY
128h	00h	Null]	14Ch	00h	System Init: None
12Ah	1 Eh	Device Geometry]	14Eh 🐇	FFh	End of CIS
12Ch	06h	Tuple Link] '	3	.	l <u> </u>
12Eh	02h	Bus: 2bytes]		W.	
130h	11h	Erase Block: 64Kbytes] "			
132h	01h	Read size: 1byte]			
134h	01h	Write size: 1byte				
136h	01h	Partation: 1block		N, Č		
138h	01h	Non-interleaved] 🏷			

Table 8. Standard CIS (Continued)

8. Card Control

8.1 Bus Operations

The host executes read, write and erase operations by issuing the appropriate command to the flash device's Command User Interface (CUI). The CUI serves as the interface between the host processor and internal operation of the flash device. These commands can be issued to the CUI using standard microprocessor bus cycles.

8.1.1 Read Array

The host enables reads from the card by writing the appropriate read command to the CUI. The Common Memory devices automatically resets to read array mode upon initial device power-up, or after reset. CE1#, CE2#, and OE# must be logically active to obtain 16 data bits at the outputs. The Card Enables (CE1# and CE2#) are used to select the addressed devices. Output Enable (OE#) is the data input/output (D0–D15) direction control, and when active, drives data from the selected memory onto the data bus. WE# must be driven to V_{IH} during a read access.

8.1.2 Output Disable

With OE# at a logic-high level (V_{IH}), the device outputs are disabled. Outputs (D0–D15) are placed in a high-impedance state.

8.2 Standby

CE1# and CE2# at a logic-high level (V_{IH}) places the card in standby mode. Standby operation disables much of the card's circuitry and substantially reduces device power consumption. The outputs (D0–D15) are placed in a high-impedance state independent of the status of OE#. If the host deselects the card during a write or erase, the card continues to function and consume normal active power until the operation completes.

8.3 Deep Power-Down

RESET at V_{IH} initiates the deep power-down mode. RESET pin is connected to Vcc with resister 250K (@Vcc=5V). When accesses the card, the system must input low level to RESET.

During reads, an active RESET deselects the memory, places output drivers in a high-impedance state, and turns off all internal circuits. RESET must be held high for a minimum of 100 ns. After returning from deep powerdown, the host must wait before initial memory access outputs are valid, as determined by t_{PHQV}. After this wakeup interval, the host can resume normal operations to the card. Card reset forces the CUI to reset to read array mode and sets the status register to 80H.

8.4 Reset

The card is in initial state directly after power-up. But we recommend to do reset operation after power-up to make sure to initialize the card.

During block erase, byte write, or lock-bit configuration modes, an active RESET will abort the operation. RDY/ BSY# remains low until the reset operation completes. Memory contents being altered are no longer valid; the data may be partially erased or written. The host must wait after RESET goes to logic-Low (V_{IL}) before it can write another command, as determined by t_{PHWL} .

It is important to assert RESET to the card during a system reset. If a CPU reset occurs without a card reset, the host will not be able to read from the card if that card is in a different mode when the system reset occurs. For example, if an end-user initiates a host reset when the card is in read status register mode, the host will attempt to read code from the card, but will actually read status register data. Sharp's ID242 Series Flash Memory Card allows proper card reset following a system reset through the use of the RESET input.

8.5 Read Identifier Codes Operation

Manufacture Code and Device Code are contained within each flash memory device in the memory card. The identifier code operation is initiated by writing the Read Identifier Codes command (90h, 9090h) into the CUI of each memory device. The specific address of each device is necessary to be selected to read these codes (Table 9).

Code	Address	Data
Manufacture Code	00000Qh	89h (8989h)
Device Code	000002h	A6h (A6A6h)

Tables 9. Identifier Codes

(): In word access mode.

bit7	bit6	bit5	bit4	bit3	bit2	bit1	bit0	
SR .7	SR.6	SR.5	SR.4	SR.3	SR.2	SR.1	SR.0	
WSMS	ESS	ECLBS	BWSLBS	VPPS	BWSS	DPS	RFU	
1 = Rei0 = BuSR.6 = ERASI1 = Era0 = EraSR.5 = ERASI1 = Err0 = SucSR.4 = BYTE1 = ErrSet0 = SucSet	ady sy E-SUSPEND S se Suspended se in Progress E AND CLEA or In Block E ccessful Block WRITE AND or in Byte Wr Block/Master ccessful Byte V Block/Master	Completed R LOCK-BITS rasure or Clear Erase or Clear SET LOCK-E ite or Lock-Bit Write or	S STATUS Lock-Bits Lock-Bits	word/byte wr SR.6-0 are in If both SR.5 at bit configur sequence was SR.3 does no level. The WS only after 1 Block/Master	t provide a co M interrogate Block Erase Lock-bit, or 3 is not gua	t configuration .7="0". "s after a block t, an impropontinuous ind s and indicate , Word/Byt Clear Lock- ranteed to re	on completion cerase or lock per command ication of V _{PP} is the V _{PP} leve e Write, Se bits command	
SR.3 =VPP S 1 = VP 0 = VP	P Low Detect	, Operation Ab	ort	and block loc master lock-bi	provide a con k-bit values. t, block lock-b	The WSM in hit, and RP# or	iterrogates the nly after Block	
1 = Byt	e Write Suspe	PEND STATU ended ogress/Complet		Erase, Word/Byte Write, or Lock-bit configuration command sequences. If informs the system, depending on the attempted operation, if the block lock-bit is set.				
RP# 0 = Unl	ster Lock-bit, Lock Detecte ock	STATUS Stock Lock-bit ed, Operation 7	887	the block lock writing the R master and blo SR.0 is reserve	it is set, and/o and master lo ead Identifier ock lock-bit sta ed for future us the status regis	ck configurati Codes comm atus. se and should	ion codes after nnad indicates	

8.6 Status Register

Each flash memory device in the card has status register. The status register may be read to determine when a write, block erase, or lock-bits configuration is complete, and whether that operation completed successfully (Please refer to Table 10). It may be read at any time by writing the Read Status Register command (70h, 7070h) into the CUI. In word access mode, the status register data of even byte devices are output to D7~0, and the status register data of odd byte devices are output to D15~8.

8.7 CUI Writes

Flash memory device operations are selected by writing specific commands (Please refer to Section 10) into the Command User Interface (CUI). The contents of the interface register serves as input to the internal state machine on each component.

The CUI itself does not occupy an addressable memory location. The interface register is a latch used to store the command, address and data information needed to execute the command. Erase Setup and Erase Confirm commands require both appropriate command data and an address within the block to be erased. The Write Setup command requires both appropriate command data and the address of the location to be written, while the Write command consists of the data to be written and the address of the location to be written.

The CUI is written by bringing WE# to a logic-low level (V_{IL}) while CE# is low. Addresses and data are latched on the rising edge of WE#. Standard microprocessor write timings are used.

When a write or erase command has been issued to the CUI, the internal Write State Machine (WSM) becomes busy and will not be ready until it has completed the operation.

8.8 Write Protect Switch

The ID242 Series Flash Memory Card has a write protect switch on the back of the card. When the switch is in the write protect position, the card blocks all writes to the common and attribute memory without Card Management Registers region (see Figure 5).



Figure 5. Write Protect Switch

9. Component Management Registers (CMR)

Component Management Registers (CMR) are mapped at even byte locations beginning at address 4000h in attribute memory.

9.1 Configuration Option Register (Address:4000h)

Address	Bit.7	Bit.6	Bit.5	Bit.4	Bit.3	Bit.2	Bit.1	Bit.0
4000h	SRESET				Reserved			
	SRESET:	1=Reset State	0=End I	Reset Cycle				

9.2 Card Configuration Register (Address:4002h)

Address	Bit.7	Bit.6	Bit.5	Bit.4	Bit.3	Bit.2	Bit.1	Bit.0
4002h			Reserved			PWDN	Rese	rved
	PWDN	1=Power-D	lown					

9.3 Socket and Copy Register (Address:4006h)

Address	Bit.7	Bit.6	Bit.6 Bit.5 Bit.4 Bit.3 Bit.2 Bit.1					
4006h	Reserved		Copy No. Soket No.					
	Soket No.: Copy No.:				.			
	The card ma	ay use to dis	tinguish betw	veen similar	cards install	ed in a syste	em.	

9.4 Card Status Register (Address:4100h)

Address	Bit.7	Bit.6	Bit.5	Bit.4	Bit.3	Bit.2	Bit.1	Bit.0
4100h	ADM	ADS	SRESET	CMWP	PWDN	CISWP	WP	RDY/BSY
	ADM:	ORed value	of the Read	y/Busy Masl	c Register.			
		1 = Any de	vice is mask	ed. $0 = All$	Devices are	not Masked.	*	
	ADS:	ORed value						
		1 = Any de	vice-pair is (Controled por	wer-down by	y bit.2 of the	Card Confi	guration
		Register.						
	SRESET:	Reflects the	bit.7 of the	Configuratio	n Option Re	gister.		
	CMWP:	Reflects the	bit.1 of the	Write Protec	tion Registe	r.		
1	PWDN:	Reflects the	bit.2 of the	Card Config	uration Regi	ster.		
	CISWP:	Reflects the	bit.0 of the	Write Protec	tion Registe	r.		
1	WP:	Indicates the	e Write Prote	ect Switch st	atus.			
		1 = Write P	rotect Swite	a; ON 1 = V	Vrite Protect	Switch: OFF	7	
	RDY/BSY:	Reflects the	Ready/Busy	Status Regi	ster.			
		1 = All dev	ces are REA	\mathbf{DY} . $0 = \mathbf{A}$	ny device is	BUSY.		

9.5 Write Protection Register (Address:4104h)

â.

Address	Bit.7	Bit.6 Bit.5	Bit.4	Bit.3	Bit.2	Bit.1	Bit.0
4104h		Reserved			BLKEN	CMWP	CISWP
\mathcal{Q}	CMWP: CISWP: C	Block Locking Enable 1 = Enable Block Lockin Common Memory Write 1 = Common Memory w Common Memory CIS W 1 = Common Memory C	Protect vithout CIS Write Protect	region in W	rite Protect S	tatus	

NOTE: ID242 series ignores BLKEN bit. Block Locking is always enable.

Also.

9. 6 Sleep Control Register (Address:4118h~411Ah)

Address	Bit.7	Bit.6	Bit.5	Bit.4	Bit.3	Bit.2	Bit.1	Bit.0	
411Ah				Rese	erved	· · · · · ·			
4118h	Rese	Reserved DEV10/11 DEV8/9 DEV6/7 DEV4/5 DEV2/3 DEV0/1							
		If set to "1 by PWDN	sleep mode de ", the corresp bit of Config bits are DEV0	onding devic uration Statu	is Register.				

•

9.7 Ready/Busy Mask Register (Address:4120h~4122h)

Address	Bit.7	Bit.6	Bit.5	Bit.4	Bit.3	Bit.2	Bit.1	Bit.0		
4122h	Reserved				DEV11	DEV10	DEV9	DEV8		
4120h	DEV7	DEV6	DEV5	DEV4	DEV3	DEV2	DEV1	DEV0		
1 = Mask the Rdy/Bsy# The corresponding device's Rdy/Bsy# signals to set bit are ignored for card's RDY/BSY# output. Available bits are DEV0 ⁻ DEV7 for 8MB, DEV0 ⁻ DEV3 for 4MB, DEV0 ⁻ DEV1 for 2MB.										

9.8 Ready/Busy Status Register (Address:4130h~4132h)

2MB.

Address	Bit.7	Bit.6	Bit.5	Bit.4	Bit.3	Bit.2	Bit.1	Bit.0
4132h		Rese	erved		DEV11	DEV10	DEV9	DEV8
4130h	DEV7	DEV6	DEV5	DEV4	DEV3	DEV2	DEV1	DEV0
				orresponding	device's Rdy 8MB, DEVO)~ DEV1 for

9.9 Ready/Busy Mode Register (Address:4140h)

		4						
Address	Bit.7	Bit.6	Bit.5	Bit.4	Bit.3	Bit.2	Bit.1	Bit.0
4140h			Reser	ved			RACK	MODE
		Must clear transition. RDY/BSY	nowledge Bit this bit after r # Mode erformance M	eceiving re	-		next device's	s ready

10. Command Definitions

Device operations are selected by writing specific commands into the Command User Interface. Table 11 defines the commands.

Command	Note	Fi	rst Bus Cy	cle	Sec	ond Bus C	ycle
Command	Note	Operation	Address	Data	Operation	Address	Data
Read Array / Reset		Write	DA	FFh (FFFFh)	-	-	-
Read Identifier Codes	1	Write	DA	90h (9090h)	Read	IA	ID
Read Status Register	2	Write	DA	70h (7070ħ)	Read	DA	SRD
Clear Status Register		Write	DA	50h (5050h)	-	-	-
Word/Byte Write	3	Write	WA	40h (4040h) or 10h (1010h)	Read	WA	WD -
Block Erase	3	Write	ВА	20h (2020h)	Write	BA	D0h (D0D0h)
Block Erase and Word/Byte Write Suspend	3	Write	DA	B0h (B0B0h)	-	-	
Block Erase and Word/Byte Write Resume	3	Write	DA	D0h (D0D0h)	-	-	-
Set Block Lock-Bit		Write	BA	60h (6060h)	Write	BA	01h (0101h)
Set Master Lock-Bit	4	Write	DA	60h (6060h)	Write	DA	F1h (F1F1h)
Clear Block Lock-Bit		Write	DA	60h (6060h)	Write	DA	D0h (D0D0h)
Address		Data	••••••••••••••••••••••••••••••••••••••				
IA =Identifier code Address		ID =	Identifier C	odes			
WA Write Address		WD =	Write Data				
BA =Block Address		SRD =	Data from S	Status Regi	ster		

Table 11. Command Definitions

Note:

DA

=Device Address

1. Following the Read Identifier Codes command, read operations access manufacture, device, block lock, and master lock codes.

- 2. Status Register may be read to determine when a write, block erase, or lock bit configuration is complete, and whether that operation completed successfully.
- 3. If the block is locked, block erase or write operations are desabled.
- 4. This command is not available for ID242 series, because the card does not possess the feature suppling 12V to RP# of common memory devices.

10.1 Read Array Command

Upon initial device power-up and after exit from deep power-down mode, the card defaults to read array mode. The host can also read by writing the Read Array command. The device remains enabled for reads until the host writes another valid command. Once the internal WSM has started a block erase, byte write or lock-bit configuration, the device will not recognize the Read Array command until the WSM completes its operation. However, the host can suspend the WSM using an Erase Suspend or Byte Write Suspend command.

10.2 Read Identifier Codes Command

The host initiates the identifier code operation by writing the Read Identifier Codes command. Following the command write, read cycles from addresses shown in Table 12 retrieve the manufacturer, device, block lock configuration and master lock configuration codes. To terminate the operation, write another valid command.

			XXX	
	Select Dvice-pair A25-A21	Address in Device A20-A1	Even#Odd A0	Data Output D7-D0
Manufacture Identifier Code	DPA	00000h	0:Even 1:Odd	89h
Device Identifier Code	DPA	00001h	0:Even 1:Odd	A6h
Block Lock Configuration		X0002h	0:Even	BLKD
	DPA	(X: Select Block)	1:Odd	D0: 0=Unlock 1=Lock D7-D1: Reserved
Master Look			0.5	MLKD
Master Lock Configuration	DPA	00003h	0:Even 1:Odd	D0: 0=Unlock 1=Lock D7-D1: Reserved

Table 12. Identifier Codes

NOTE: A0 is ignored in word access mode, and D15-D8 outputs the Odd byte data.

DPA Address as select device pair

BLKD: Block Lock Configuration Data

MLKD: Master Lock Configuration Data

10.3 Read Status Register Command

The common memory components on this Flash Memory Card each contain a Status Register which may be read to determine when a write, block erase, or lock bit configuration is complete, and whether that operation completed successfully (see Table 8). The host may read the Status Register at any time by writing the Read Status Register command to the CUI. After writing this command, all subsequent read operations output data from the Status Register, until the host writes another valid command to the CUI. The flash components latch the contents of the Status Register on the falling edge of OE# or CE#, whichever occurs first. OE# or CE# must be toggled to V_{IH} before further reads to update the Status Register latch.

NOTE:

Both status registers need to be checked when determining the status of a \times 16 erase/write operation.

10.4 Clear Status Register Command

The WSM sets the Erase Status and Write Status bits to "1"s and they can only be reset by the Clear Status Register command. The WSM sets these bits to "1" when a write or erase operation has failed. The host can issue additional write and erase commands to the CUI without clearing the status register. This allows a system to write a sequence of bytes before checking the write status bit. However, if an error has occurred the system will not know which write in the sequence has failed. To clear the Status Register, the Clear Status Register command (5050H) is written to the CUI.

10.5 Block Erase Command

The host executes an erase command one block at a time using a two-cycle command. The host writes a block erase setup command first, followed by a block erase confirm command. These two commands require appropriate sequencing and an address within the block to complete (erase changes all block data to FFH). The WSM handles block preconditioning, erase, and verify internally (invisible to the system). After the host writes the twocycle block erase sequence, the device automatically outputs status register data when read. The CPU can detect block erase completion by analyzing the output data of the RDY/BSY# signal or status register bit SR.7.

When the block erase completes, status register bit SR.5 should be checked. If a block erase error is detected, the host should clear the status register before system software attempts corrective actions. The CUI remains in read status register mode until the host issues a new command

This two-step command sequence of setup followed by execution ensures that block contents are not accidentally erased. An invalid Block Erase command sequence will result in the WSM setting status register bits SR.4 and SR.5 to "1". Successful block erase requires that the corresponding block lock-bits is not set. If the host attempts a block erase when the corresponding block lock-bit is set, the WSM will set SR.1 and SR.5 to "1".

10.6 Word/Byte Write Command

The host executes a word write by a two-cycle command sequence. The host writes word write setup (standard 4040H or alternate 1010H) first, followed by a second write that specifies the address and data (latched on the rising edge of WE#). The WSM then takes over, controlling the word write and write verify algorithms internally. After the host writes the word write sequence, the device automatically output status register data when read. The CPU can detect the completion of the byte write event by analyzing the RDY/BSY# pin or status register bit SR.7. When the WSM completes the word writes, the host should check status register bit SR.4. If the host detects a write error, it should clear the status register. The internal WSM verify only detects errors for "1"s that do not successfully writes to "0"s. The CUI remains in read status register mode until it receives another command. Successful word writes requires that the corresponding block lock-bit is not set. If the host attempts a write when the corresponding block lock-bit is not set. If the host attempts a write when the corresponding block lock-bit is set, the WSM will set SR.1 and SR.4 "1".

10. 7 Block Erase Suspend Command

The Block Erase Suspend command allows block-erase interruption to read or write data in another block of memory. Once the block erase process starts, writing the Block Erase Suspend command requests that the WSM suspend the block erase sequence at a predetermined point in the algorithm. After the host writes the Block Erase

Suspend command, the host should then write the Read Status Register command. Polling status register bits SR.7 and SR.6 can determine when the WSM suspends the block erase operation (both will be set to "1"). RDY/BSY# will also transition to V_{OH} Specification t_{WHRH2} defines the block erase suspend latency. It is also possible that the block erase completes before the device has an opportunity to suspend. The host should also check for this condition.

After the block erase has been suspended, the host can issue a read array command or a word write command to any block except the one that has been suspended. Using the Word Write Suspend command (see Section 8.8), a word write operation can also be suspended. During a word write operation with block erase suspended, status register bit SR.7 will return to "0" and the RDY/BSY# output will transition to V_{OL} . However, SR.6 will remain "1" to indicate block erase suspend status. The only other valid commands while block erase is suspended are Read Status Register and Block Erase Resume. After the host writes a Block Erase Resume command to the flash memory, the WSM will continue the block erase process. Status register bits SR.6 and SR.7 will automatically clear and RDY/BSY# will return to V_{OL} . After the host writes the Erase Resume command, the device automatically outputs status register data when read. Block erase cannot resume until word write operation initiated during block erase suspend have completed.

10. 8 Word/Byte Write Suspend Command

The Word Write Suspend command allows word write interruption to read data in other flash memory locations. Once the word write process starts, writing the Word Write Suspend command requests that the WSM suspend the word write sequence at a predetermined point in the algorithm. After the host writes the Word Write Suspend command, it should write the Read Status Register command. Polling status register bits SR.7 and SR.2 can determine when the WSM suspends the byte write operation (both will be set to "1"). RDY/BSY# will also transition to V_{OH} . Specification t_{WHRH1} defines the word write suspend latency. It is also possible that the word write completes before the device has an opportunity to suspend. The host should also check for this condition. After the word write has been suspended, the host can write the Read Array command to read data from any location except the suspended location. The only other valid commands while word write is suspended are Read Status Register and Word Write Resume. After the host writes a Word Write Resume to the CUI, the WSM will continue the word write process. Status register bits SR.2 and SR.7 will automatically clear and RDY/BSY# will return to V_{OL} . After the host writes the Word Write Resume command, the device automatically outputs status register data when read.

10.9 Set Block Lock-Bit Command

The host can enable a flexible block locking and unlocking scheme using the Set Block Lock-Bit command. This command enables the host to lock individual blocks within the flash array. The block lock-bits gate program and erase operations.

The host sets the block lock-bit using a two-cycle command sequence. The host writes the set block lock-bit setup command along with the appropriate block or device address. This command is followed by the set block lock-bit confirm command (and an address within the block to be locked). The WSM controls the set lock-bit algorithm. After the host completes the command sequence, the card automatically outputs status register data when read. The CPU can detect the completion of the set lock-bit event by analyzing the RDY/BSY# pin output or status

23

register bit SR.7.

When the WSM completes the set lock-bit operation, the host should check status register bit SR.4. If the host detects an error it should clear the status register. The CUI will remain in read status register mode until the host issues a new command.

This two-step sequence of setup followed by execution ensures that the host does not accidentally set the lockbits. An invalid Set Block Lock-Bit command will result in the WSM setting status register bits SR.4 and SR.5 to "1".

10. 10 Set Master Lock-Bit Command

A successful set block lock-bit operation of the memory card requires that the master lock-bit be cleared or, if the master lock-bit is set, that RP# of common memory device is Vcc. RP# of common memory device can only accept Vcc or be connected to GND. The RP# will not accept 12V. If it is attempted with the master lock-bit set and RP#=12V, SR.1 and SR.4 will be set to "1" and operation will fail.

10.11 Clear Block Lock-Bits Command

The host clears all set block lock-bits in parallel using the Clear Block Lock-Bits command. The host is free to clear block lock-bits using the Clear Block Lock-Bits command.

The host executes the clear block lock-bits operation using a two-cycle command sequence. The host must first issue a Clear Block Lock-Bits setup command. This command is followed by a confirm command. After the host completes the two-cycle command sequence, the device automatically outputs status register data when read. The CPU can detect completion of the clear block lock-bits event by analyzing the RDY/BSY# pin output or status register bit SR.7.

When the WSM completes the operation, the host should check status register bit SR.5. If the host detects a clear block lock-bit error, the host should clear the status register. The CUI will remain in read status register mode until the host issues another command.

This two-step sequence of setup followed by execution ensures that the host does not accidentally clear block lock-bits. An invalid Clear Block Lock-Bits command sequence will result in the WSM setting status register bits SR.4 and SR.5 to "1".

If a clear block lock-bits operation is aborted due to V_{CC} transitioning out of valid range or RESET active transition, block lock-bit values are left in an undetermined state. The host must repeat the clear block lock-bits command to initialize block lock-bit contents to known values.



25



Note) *1. Write FFFFH after the last block erase operation to reset the device to Read Array Mode. *2. If error is detected, clear the Status Register before attempting retry or other error recovery.

11. Electrical Specifications

11.1 Absolute Maximum Ratings

PARAMETER	NOTE	SYMBOL	RATING	UNIT
Supply Voltage	2	V _{cc}	-0.3 to 6.0	V
Program Voltage	2	V _{pp}	-2.0 to 14.0	v
Input Voltage	2	V _{IN}	-0.3 to Vcc+0.3(Max:6.0)	v
Operating Temperature	1	T _{OPR}	0 to 60	°C
Storage Temperature		T _{stg}	-20 to 65	°C

NOTES:

- 1. Operating temperature is for commercial product defined by this specification.
- 2. All specified voltages are with respect to GND. During transitions, this level may undershoot to -2.0v for periods <20ns or overshoot to Vcc+2.0v for periods <20ns.

11.2 Recommended Operating Conditions

PARAMETER	NOTE	SYMBOL	MIN		UNIT
		V _{cci}	0.6	3.6	v
Supply Voltage		V _{ccz}	4.75	5.25	V
		Vices	4.5	5.5	v
		V	3.0	3.6	V
Program Voltage		V _{PP2}	4.5	5.5	v
		V _{PP3}	11.4	12.6	V
Operating Temperature		T _{opr}	0	60	°C

11.3 Capacitance

Ta=25℃, f=1MHz PARAMETER SYMBOL MIN TYP MAX UNIT CONDITION Input Capacitance C 15 -pF V_{IN}=0.0V Input/Output Capacitance 25 V_{out}=0.0V C_{io} -pF

11.4 AC Input/Output Test Conditions



Figure 8. Transient Input/Output Reference Waveform

Figure 8 shows Input/Output level and test level for AC test. Input rise and fall times (10% to 90%) < 10ns.

12. DC Characteristics

Input Low Voltage	BOL V _{IL} V _{IH} -I _{IL1} -I _{IL2}	TE 1 1 2	ty	MIN	MAX	MIN	MAX		
Input High Voltage	V _{IH} -I _{ILI}	1			0.011		1711 N2 K		
Input Low Current	-I _{ILI}				0.3Vcc		1.5	V	
		2		0.7Vcc		3.5		V	
-	$-I_n$	2			± 2.0		± 2.0	μA	$V_I = 0V$
	کي ا	3		2.0	30.0	8.0	60.0	μA	$V_1 = 0V$
Input High Current	I _{DH1}	3			± 2.0		± 2.0	μA	$V_{ij} = Vcc$
	I _{IH2}	2		2.0	30.0	8.0	60.0	μA	V _a = Vcc
Output Low Voltage	V _{oli}	4,5			-		0.4	V	I _{oL} = 6mA
Output Low Voluge	OLI	Ч,-			0.4			X	$I_{oL} = 3mA$
	V _{ohi}	4		-		4.0		V	I _{он} = -3mA
Output High Voltage	• оні	-		Vcc-0.5		-			$I_{OH} = -1.5 mA$
	v	5		-		4.0		v	I _{oH} = -6mA
	V _{OH2}	5		Vcc-0.5		-		V	I _{oH} = -3mA
			2MB		240		240	μA	CE,#,CE,#=Vcc
Vcc Stand-by Current I	I _{ccs}	6	4MB	4	450		450	μΑ	$A_0 \sim A_{25} = \tilde{G}ND$
			8MB	1	850		850	μA	I _{our} =0mA
			2MB		45		75	μA	RESET=Vcc
Vcc Deep Power-Down Current	I _{CCD}	6	4MB		70		110	μA	CE ₁ #,CE ₂ #=Vcc A ₀ ~A ₂₅ =GND
			8MB		» 1 5 0		200	μA	$I_{0} = 0 \text{mA}$
Vcc Read Current I	I _{ccr}	6,8			90		100	mA	$CE_1 #, CE_2 #=GND$ $I_{OUT} = 0mA$
					35		-	mA	$V_{pp} = 3.3V \pm 0.3V$
Vcc Word Write or Set Lock-Bit Current	Locx	69			35		75	mA	$V_{pp} = 5.0V \pm 10\%$
					25		65	mA	$V_{pp} = 12.0V \pm 5\%$
	/				35		-	mA	$V_{pp} = 3.3V \pm 0.3V$
Vcc Block Erase or Clear Lock-Bit Current		6,9			35		65	mA	$V_{pp} = 5.0V \pm 10\%$
	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~				25		55	mA	$V_{pp} = 12.0V \pm 5\%$
VccWord Write of Block Erase Suspend Current	[ _{CCWS} [ _{CCES}	6			13		21	mA	
Vcc Lockout Voltage	V _{lko}			2.0		2.0		v	

(Continue to next page)

PARAMETER	SYM-		Densi-	Vcc=3.3	V±0.3V	Vcc=5 Vcc=5V		UNIT	TEST CONDITION	
	BOL	TE	ty	MIN	MAX	MIN	MAX			
		1	2MB		± 30		± 30	μ Α		
			4MB		±60		±60	μA	$V_{pp} \leq Vcc$	
V _{pp} Stand-by or Read	IPPS	6	8MB		± 150		±150	μA		
Current	I		2MB		0.4		0.4	mA		
			4MB		0.8		0.8	mA	V _{pp} >Vcc	
			8MB		1.6		1.6	mA		
	I _{PPD}		2MB		10		10	μA		
V _{PP} Deep Power-Down Current		6	4MB		20		20	μΑ		
			8MB		50		50	µА	*	
					80		-	mA	$V_{pp} = 3.3V \pm 0.3V$	
V _{pp} Word Write or Set Lock-Bit Current	I	6,9			80	4	80	mA	$V_{pp}$ =5.0V±10%	
					32	4	32	≫mA	$V_{pp} = 12.0V \pm 5\%$	
					40		-	mA	$V_{pp} = 3.3V \pm 0.3V$	
V _{pp} Block Erase or Clear Lock-Bit Current	I _{ppe}	6,9			40		40	mA	$V_{pp} = 5.0V \pm 10\%$	
					32		32	mA	$V_{pp} = 12.0V \pm 5\%$	
			2MB	-	400		400	μA		
			4MB		430	*	430	μA	V _{pp} ≦ Vcc	
V _{pp} Word Write or Block Erase Suspend	I	6	8MB		500		500	μA		
Current	I _{ppes}	0	2MB		0.4		0.4	mA	V _{pp} >Vcc	
		4	4MB		0.8		0.8	mA		
			8MB		1.6		1.6	mA		
V _{pp} Lockout Voltage	V	7,9	. 🔌		1.5		1.5	v		

NOTE:

- 1. These parameters are applied to all input pins and all i/put/output pins in input mode.
- 2. These parameters are applied to  $A_0 \sim A_{25}$  and  $D_0 \sim D_{15}$  in input mode.
- 3. These parameters are applied to CE,#,CE,#,WE#,OE#,REG# and RESET.
- 4. These parameters are applied to RDY/BSY#.
- 5. These parameters are applied to  $D_0 \sim D_{15}$  in output mode.
- 6. All currents are in RMS unless otherwise notes.
- Block erase, word/byte write, and lock-bit configurations are inhibited when V_{PP} ≤ V_{PPLK}, and guaranteed in . the V_{PP} Voltage is V_{PP1}, V_{PP2} or V_{PP3}.
- 8. Automatic Power Savings(APS) reduces typical I_{CCR} to 30mA at Vcc=5V and 20mA at Vcc=3.3V in static operation.
- 9. Sampled.

#### **13. AC Characteristics Testing Conditions**: 1) Input Pulse Level 1.5 to 3.5V (@Vcc=5V±5%,Vcc=5V±10%) : $0 \text{ to } 3.0 \text{V} (@\text{Vcc}=3.3\pm0.3 \text{V})$ 2) Input Rise/Fall Time 10ns : 3) Input/Output Timing Reference Level : 2.5V (@Vcc=5V±5%,Vcc=5V±10%) $1.5V @Vcc=3.3V\pm0.3V$ 4) Output Load 1TTL+100pF (@Vcc=5V±5%,Vcc=5V±10%) : (including scope and jig capacitance) 1TTL+50pF (@Vcc=3.3V±0.3V)

### 13.1 Common and Attribute Memory Read Operations

 $(Ta = 0 \text{ to } 60^{\circ}C)$ 

								1a - 0 w	00 C)
	SYM	IBOL	Vcc=3.3	V±0.3V	Vcc=5	V±5%	» Vcc=5	V±10%	
PARAMETER	IEEE	JEIDA/ PCMCIA	MIN	MAX	MIN	MAX	MIN	MAX	Unit
Read Cycle Time	t _{avav}	t _{eR}	250	- <b>A</b>	150	-	160	-	
Address Access Time	t _{avqv}	t _a (A)	-	250		150	-	160	
CE# Access Time	t _{elqv}	t _a (CE)		250	🔊 -	150	-	160	1
OE# Access Time	t _{GLQV}	t _a (OE)		125	-	75	-	80	
Output Disable Time from CE1#,CE2# *	t _{ehqz}	t _{dis} (CE)		100	-	75	-	80	
Output Disable Time from OE# *	t _{ghqz}	ŧ _{as} (OE)		100	-	75	-	80	ns
Output Enable Time from CE1#,CE2#	t _{elowiz}	t _{en} (CE)	5	-	5	-	5	-	
Output Enable Time from OE#	t _{gl@NZ}	t _{en} (OE)	5	-	5	-	5	-	
Data Valid Time from Address Change		t _v (A)	0	-	0	-	0	-	
RESET Recovery Time to Output Delay	е Рног		-	700	-	450	-	450	

*: Time until output becomes floating. (The output voltage is not defined.)



31

## 13.2 Command Write Operations : Common Memory

### 13. 2. 1 WE# Controlled Write Operations

Address Setup Time $t_{w}(A)$ 30       -       ns         Write Recovery Time $t_{wAX}$ $t_{ee}(WE)$ 30       -       ns         Data Setup Time for WE# $t_{w(D)}$ $t_{ue}(D)$ 30       -       ns         Data Setup Time for WE# $t_{w(D)}$ 30       -       ns         Data Hold Time $t_{w(D)}$ 30       -       ns         OE# Hold Time for $t_{w(RL)}$ $t_{(OE-WE)}$ 120       -       ns         CE# Setup Time for WE# $t_{u(CE-WEH)$ 180       -       ns         Address Setup Time for $t_{wwwith}$ $t_{u}(A-WEH)$ 180       -       ns         We# Palse Width $t_{w_{uax}}$ $t_{u}(WE)$ 150       -       ns         We# High to RDY/BSY# $t_{wuax}$ $t_{uwax}$ 1       - $\mu_{us}$ Vps Setup Time $t_{vpwat}$ $t_{wuax}$ -       140       ns         Vps Setup Time $t_{vpwat}$ $t_{uwax}$ -       140       ns         Vps Setup Time $t_{vpwat}$ $t_{vpwat}$ 0       -       ns         Vps Setup Time <td< th=""><th></th><th>· · · -</th><th></th><th></th><th>· · · · · · · · · · · · · · · · · · ·</th><th>$3.3 \vee \pm 0.3 \vee$, $1a=0$ to</th><th>000)</th></td<>		· · · -			· · · · · · · · · · · · · · · · · · ·	$3.3 \vee \pm 0.3 \vee$ , $1a=0$ to	000)
IEEE         PCMCIA         MIN         MAX           Write Cycle Time $t_{AVWL}$ $t_{w}$ 250         -         ns           Address Setup Time $t_{AVWL}$ $t_{w}(A)$ 30         -         ns           Write Recovery Time $t_{wrext}$ $t_{w}(WE)$ 30         -         ns           Data Setup Time for WE# $t_{wrext}$ $t_{w}(D)$ 30         -         ns           Data Hold Time $t_{wrext}$ $t_{a}(D)$ 30         -         ns           CE# Setup Time for WE# $t_{wrext}$ $t_{a}(OE-WE)$ 20         -         ns           CE# Setup Time for WE# $t_{a}(OE-WE)$ 20         -         ns           Address Setup Time for WE# $t_{a}(A-WEH)$ 180         -         ns           Write Pulse Width $t_{a}(A-WEH)$ 180         -         ns           We## High to RDY/BSY# $t_{w}(A-WEH)$ 180         -         ns           Wer# High to RDY/BSY# $t_{w}(A-WEH)$ 180         -         ns           Word/Byte Write Time $t_{wrov1}$ $V_{w}=3.3V \pm 0.3V$ 1.5         -	PARAMETER	5	SYMBOL	CONDITION	Vcc=3.3	V±0.3V	Unit
Address Setup Time $t_{AVWL}$ $t_{u}(A)$ 30       -       ns         Write Recovery Time $t_{wHAX}$ $t_{w}(WE)$ 30       -       ns         Data Setup Time for WE# $t_{wNEX}$ $t_{(D)}$ 30       -       ns         Data Hold Time $t_{wHEX}$ $t_{(D)}$ 30       -       ns         OE# Hold Time for WE# $t_{wHEX}$ $t_{(OE-WE)$ 120       -       ns         CE# Setup Time for WE# $t_{u}(CE-WEH)$ 180       -       ns         Address Setup Time for $t_{avwH}$ $t_u(CE-WEH)$ 180       -       ns         Write Pulse Width $t_{wLWH}$ $t_u(WE)$ 150       -       ns         We# High to RDY/BSY# $t_wHEL$ -       140       ns         RESET Recovery Time $t_{pWL}$ -       140       ns         Vps Setup Time $t_{vpWL}$ 0       -       ns         Vps Hold Time $t_{vpWL}$ 0       -       ns         Vps Setup Time $t_{vpWL}$ Vps = 3.3 V ± 0.3 V       1.5       - $\mu_{sS}$ Vps Hold Time $t_{vpWQ}$ Vps = 3.		IEEE	PCMCIA	CONDITION	MIN	MAX	Omt
Address Setup Time $t_{xVWL}$ $t_{u}(A)$ 30       -       ns         Write Recovery Time $t_{WHAX}$ $t_{u}(WE)$ 30       -       ns         Data Setup Time for WE# $t_{pvWR}$ $t_{u}(D-WEH)$ 80       -       ns         Data Hold Time $t_{wHXX}$ $t_u(D-WEH)$ 80       -       ns         Def Hold Time for WE# $t_{u}(D-WEH)$ 30       -       ns         CE# Setup Time for WE# $t_{u}(CE-WE)$ 120       -       ns         Address Setup Time for WE# $t_{u}(CE-WEH)$ 180       -       ns         Address Setup Time for WE# $t_{u}(A-WEH)$ 180       -       ns         WE#       Wite Pulse Width $t_{wLW}$ $t_u(A-WEH)$ 180       -       ns         WE# High to RDY/BSY# $t_{wRRL}$ 1       - $\mu_{SS}$ ns         Vps Setup Time $t_{vpWr}$ $v_{we}$ 0       -       ns         Vps Setup Time $t_{vpWr}$ $v_{we}$ 0       -       ns         Vsp Setup Time $t_{vpWr}$ $v_{vp}$ 10       - $\mu_{sS}$ Vsp Setu	Write Cycle Time	t _{AVAV}	t _{ew}		250	-	ns
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Address Setup Time		t _{su} (A)		30	-	ns
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Write Recovery Time	t _{whax}	t _{rec} (WE)		30	- -	ns
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Data Setup Time for WE#		t _{su} (D-WEH)		80	-	ns
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Data Hold Time	t _{whDX}	t _h (D)		30	-	ns
$\begin{array}{c c c c c c c c c c c c c c c c c c c $			ι _μ (OE-WE)		120	-	ns
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	CE# Setup Time for WE#	t _{elwh}	t _{su} (CE-WEH)		180	×	ns
WE# High to RDY/BSY# going Low $w_{WRL}$ -       140       ns         RESET Recovery Time $t_{PHWL}$ 1       - $\mu$ s         Vpp Setup Time $t_{VPWH}$ 180       -       ns         Vpp Hold Time $t_{QVVL}$ 0       -       ns         Word/Byte Write Time $t_{VPWH}$ 15       - $\mu$ s         Word/Byte Write Time $t_{WHQV1}$ $V_{pp}$ =3.3V±0.3V       15       - $\mu$ s         Block Erase Time $t_{WHQV2}$ $V_{pp}$ =5V±10%       8.2       - $\mu$ s         Vpp=12V±5%       6.7       - $\mu$ s $V_{pp}$ =5V±10%       1.0       -       s         Block Erase Time $t_{WHQV2}$ $V_{pp}$ =5V±10%       1.0       -       s       s         Set Lock-Bit Time $t_{WHQV3}$ $V_{pp}$ =3.3V±0.3V       18       - $\mu$ s         Clear Block Lock-Bits $t_{WHQV4}$ $V_{pp}$ =3.3V±0.3V       1.5       -       s         Vpp=5V±10%       1.0       - $\mu$ s $V_{pp}$ =5V±10%       1.0       - $\mu$ s         Set Lock-Bits $t_{WHQV4}$ $V_{pp}$ =5.V±10%       1.0       - <td>-</td> <td></td> <td>t_{su}(A-WEH)</td> <td>5</td> <td>180</td> <td>-</td> <td>ns</td>	-		t _{su} (A-WEH)	5	180	-	ns
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Write Pulse Width	t _{wl.wh}	t _w (WE)		150	-	ns
Vpp Setup Time       tvpwh       180       -       ns $V_{pp}$ Hold Time $t_{QVVL}$ 0       -       ns         Word/Byte Write Time $t_{QVVL}$ 0       - $\mu_s$ Word/Byte Write Time $t_{WHQV1}$ $V_{pp}=3.3V\pm0.3V$ 15       - $\mu_s$ Block Erase Time $t_{WHQV2}$ $V_{pp}=5V\pm10\%$ $8.2$ - $\mu_s$ $V_{pp}=12V\pm5\%$ $6.7$ - $\mu_s$ $V_{pp}=3.3V\pm0.3V$ $1.5$ - $s$ Block Erase Time $t_{WHQV2}$ $V_{pp}=5V\pm10\%$ $1.0$ - $s$ $V_{pp}=12V\pm5\%$ $0.8$ - $s$ Set Lock-Bit Time $t_{WHQV3}$ $V_{pp}=5V\pm10\%$ $11.2$ - $\mu_s$ $V_{pp}=12V\pm5\%$ $9.7$ - $\mu_s$ $V_{pp}=3.3V\pm0.3V$ $1.5$ - $s$ Clear Block Lock-Bits $t_{WHQV4}$ $V_{pp}=5V\pm10\%$ $1.0$ - $s$	-					140	ns
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	RESET Recovery Time	t _{phwl}			1	-	μs
Word/Byte Write Time $v_{whQV1}$ $v_{pp}=3.3V\pm0.3V$ 15 $ \mu$ s         Word/Byte Write Time $v_{whQV1}$ $v_{pp}=5V\pm10\%$ $8.2$ $ \mu$ s         Block Erase Time $v_{pp}=3.3V\pm0.3V$ $1.5$ $ \mu$ s $v_{pp}=5V\pm10\%$ $0.3V$ $1.5$ $ s$ $v_{pp}=5V\pm10\%$ $1.0$ $ s$ $v_{pp}=5V\pm10\%$ $1.0$ $ s$ $v_{pp}=3.3V\pm0.3V$ $1.8$ $ \mu$ s         Set Lock-Bit Time $v_{whQV3}$ $v_{pp}=5V\pm10\%$ $11.2$ $ \mu$ s $v_{pp}=12V\pm5\%$ $9.7$ $ \mu$ s $v_{pp}=3.3V\pm0.3V$ $1.5$ $ \mu$ s         Clear Block Lock-Bits $v_{whQV4}$ $v_{pp}=5V\pm10\%$ $1.0$ $ s$ $v_{pp}=5V\pm10\%$ $1.0$ $ s$ $v_{pp}=5V\pm10\%$ $1.0$ $ s$	V _{pp} Setup Time	t _{vpwh}	-		180		ns
Word/Byte Write Time $v_{wHQV1}$ $v_{pp}=3.3V \pm 0.3V$ 15 $\mu$ s         Word/Byte Write Time $v_{wHQV1}$ $v_{pp}=5V \pm 10\%$ $8.2$ $\mu$ s         Block Erase Time $v_{pp}=12V \pm 5\%$ $6.7$ $\mu$ s         Set Lock-Bit Time $v_{wHQV3}$ $v_{pp}=3.3V \pm 0.3V$ $1.5$ s         V_{pp}=12V \pm 5\% $0.8$ s       s         V_{pp}=12V \pm 5\% $0.8$ $\mu$ s         V_{pp}=12V \pm 5\% $0.7$ $\mu$ s         V_{pp}=12V \pm 5\% $9.7$ $\mu$ s         V_{pp}=12V \pm 5\% $9.7$ - $s$ V_{pp}=5V \pm 10\% $1.0$ s         V_{pp}=5V \pm 10\% $1.0$ s	V _{pp} Hold Time	t _{QVVL}			0	-	ns
$\frac{1}{V_{pp}=12V\pm5\%} = \frac{6.7}{6.7} = -\frac{\mu s}{4}$ Block Erase Time $\frac{1}{V_{pp}=3.3V\pm0.3V} = \frac{1.5}{1.0} = -\frac{1}{5}$ $\frac{1}{V_{pp}=5V\pm10\%} = \frac{1.0}{1.0} = -\frac{1}{5}$ $\frac{1}{V_{pp}=12V\pm5\%} = \frac{1.0}{0.8} = -\frac{1}{5}$ $\frac{1}{V_{pp}=3.3V\pm0.3V} = \frac{1.2}{1.0} = -\frac{1}{5}$ $\frac{1}{V_{pp}=12V\pm5\%} = \frac{1.2}{10\%} = \frac{1.2}{11.2} = -\frac{1}{5}$ $\frac{1}{V_{pp}=12V\pm5\%} = \frac{1.2}{10\%} = \frac{1.2}{11.2} = -\frac{1}{5}$ $\frac{1}{V_{pp}=12V\pm5\%} = \frac{1.5}{9.7} = -\frac{1}{5}$ $\frac{1}{V_{pp}=12V\pm5\%} = \frac{1.5}{9.7} = -\frac{1}{5}$ $\frac{1}{V_{pp}=5V\pm10\%} = \frac{1.5}{1.0} = -\frac{1.5}{5}$ $\frac{1}{V_{pp}=5V\pm10\%} = \frac{1.0}{1.0} = -\frac{1}{5}$ $\frac{1}{V_{pp}=5V\pm10\%} = \frac{1.0}{1.0} = -\frac{1}{5}$				V _{pp} =3.3V±0.3V	15	—	μs
$\frac{V_{pp}=12V\pm5\%}{V_{pp}=3.3V\pm0.3V}  \begin{array}{c} 6.7 & - & \mu \text{ s} \\ \hline \\ \Psi \text{ s} \\ \Psi \text{ s} \\ \hline \\ \Psi \text{ s} \\ \hline \\ $	Word/Byte Write Time	t _{whqv1}		V _{PP} =5V±10%	8.2	_	μs
Block Erase Time $t_{wHQV2}$ $v_{PP}=5V\pm10\%$ $1.0$ $ s$ $V_{PP}=12V\pm5\%$ $0.8$ $ s$ Set Lock-Bit Time $t_{wHQV3}$ $V_{PP}=3.3V\pm0.3V$ $18$ $ \mu$ s $V_{PP}=5V\pm10\%$ $11.2$ $ \mu$ s $V_{PP}=12V\pm5\%$ $9.7$ $ \mu$ s         Clear Block Lock-Bits $t_{wHQV4}$ $V_{PP}=3.3V\pm0.3V$ $1.5$ $ s$ $V_{PP}=5V\pm10\%$ $1.0$ $ s$ $v_{PP}=5V\pm10\%$ $1.0$ $ s$				V _{pp} =12V±5%	6.7	—	μs
Image: Normal state of the state of th				V _{pp} =3.3V±0.3V	1.5	—	S
$\frac{V_{pp}=12V\pm5\%}{V_{pp}=3.3V\pm0.3V} \frac{0.8}{18} - \frac{5}{10.8}$ Set Lock-Bit Time $t_{WHQV3}$ $\frac{V_{pp}=3.3V\pm0.3V}{V_{pp}=5V\pm10\%} \frac{11.2}{11.2} - \frac{1}{10.8}$ Clear Block Lock-Bits $t_{WHQV4}$ $\frac{V_{pp}=3.3V\pm0.3V}{V_{pp}=5V\pm10\%} \frac{1.5}{1.0} - \frac{5}{1.0}$	Block Erase Time	t.		V _{PP} =5V±10%	1.0	—	s
Set Lock-Bit Time $V_{wHQV3}$ $V_{pp}=5V\pm10\%$ 11.2 $ \mu$ s $V_{pp}=12V\pm5\%$ 9.7 $ \mu$ s         Clear Block Lock-Bits $V_{pp}=3.3V\pm0.3V$ 1.5 $-$ s $V_{pp}=5V\pm10\%$ 1.0 $-$ s				V _{PP} =12V±5%	0.8		S
V _{PP} =12V±5%         9.7         - $\mu$ s           Clear Block Lock-Bits Time $v_{PP}=3.3V\pm0.3V$ 1.5         -         s           V _{PP} =5V±10%         1.0         -         s				V _{pp} =3.3V±0.3V	18	—	μs
V _{PP} =12V±5%         9.7         - $\mu$ s           Clear Block Lock-Bits Time $v_{PP}=3.3V\pm0.3V$ 1.5         -         s           V _{PP} =5V±10%         1.0         -         s	Set Lock-Bit Time	t WHQV3		V _{pp} =5V±10%	11.2		μs
Clear Block Lock-Bits Time $V_{pp}=5V\pm10\%$ 1.0 — s				V _{PP} =12V±5%	9.7		μs
Time $v_{pp}=3v \pm 10\%$ 1.0 S				V _{PP} =3.3V±0.3V	1.5	_	s
		t _{whq∨4}		V _{PP} =5V±10%	1.0		s
V _{pp} -12V = 570 0.0 5				V _{PP} =12V±5%	0.8		s

 $(Vcc=3.3V\pm0.3V, Ta=0 \text{ to } 60^{\circ}C)$ 

.

$(\sqrt{cc}-3\sqrt{-5})^{2}, \sqrt{cc}=3\sqrt{-10}^{2}, 1a=0$						1a = 0.00	0000)	
PARAMETER	5	SYMBOL	CONDITION	Vcc=5	V±5%	Vcc=5	V±10%	TInit
	IEEE	PCMCIA	CONDITION	MIN	MAX	MIN	MAX	Unit
Write Cycle Time	t _{AVAV}	t _{cw}		150	-	150	-	ns
Address Setup Time	t _{AVWL}	t _{su} (A)		20	-	20	-	ns
Write Recovery Time	t _{whax}	t _{rec} (WE)		20	-	20	-	ns
Data Setup Time for WE#	t _{DVWH}	t _{su} (D-WEH)		50	-	50	-	ns
Data Hold Time	t _{whdx}	t _h (D)		20	-440000	20	-	ns
OE# Hold Time from WE#	t _{whgl}	t _h (OE-WE)		80		80	-	ns
CE# Setup Time for WE#	t _{elwh}	t _{su} (CE-WEH)		100		× 100	-	ns
Address Setup Time for WE#	t _{avwh}	t _{su} (A-WEH)	<	100		100	-	ns
Write Pulse Width	t _{wlwh}	t _w (WE)		80	-	80	-	ns
WE# High to RDY/BSY# going Low	t _{whrl}			<u> </u>	140	-	140	ns
RESET Recovery Time	t _{phwl}			1	-	1	-	μs
V _{pp} Setup Time	t _{vpwh}	-		100	-	100	-	ns
V _{PP} Hold Time	t _{qvvl}			0	-	0	-	ns
			¥ _{₽₽} =5V±10%	6.5	-	6.5	-	μs
	t _{whqv1}		$V_{pp} = 12V \pm 5\%$	4.8	-	4.8	-	μs
Block Erase Time			V _{pp} =5V±10%	0.9	-	0.9	-	s
Block Eldse Thile	WHQV2		V _{pp} =12V±5%	0.3	-	0.3	-	S
Set Lock-Bit Time			V _{pp} =5V±10%	9.5	_	9.5	-	μs
Set Lock Dit Time	twhqv3		V _{pp} =12V±5%	7.8	-	7.8	-	μs
Clear Block Lock-Bits	t		V _{pp} =5V±10%	0.9	-	0.9	-	s
Time	t WHQV4		V _{pp} =12V±5%	0.3	-	0.3	-	S

 $(Vcc=5V\pm5\%, Vcc=5V\pm10\%, Ta = 0 \text{ to } 60^{\circ}C)$ 

٠



## 13. 2. 2 CE# Controlled Write Operations

	SYMBOL			Vcc=3.3	T		
PARAMETER	IEEE	PCMCIA	CONDITION	MIN	MAX	— Unit	
Write Cycle Time	t _{avav}	t _{cw}		250	-	ns	
Address Setup Time	t _{AVEL}	t _{su} (A)		30	-	ns	
Write Recovery Time	t _{ehax}	t _{rec} (CE)		30	- -	ns	
Data Setup Time for CE#	t _{DVEH}	t _{su} (D-CEH)		60	-	ns	
Data Hold Time	t _{endx}	t _h (D)		30	-	ns	
OE# Hold Time from CE#	t _{ehgl}	t _h (OE-CE)		120	-	ns	
WE# Setup Time for CE#	t _{wleh}	t _{su} (WE-CEH)		<b>180</b>	-	ns	
Address Setup Time for CE#	t _{aven}	t _{su} (A-CEH)	ł	180	-	ns	
Write Pulse Width	t _{eleh}	t _w (CE)	- An	150>	-	ns	
CE# High to RDY/BSY# going Low	t _{ehrl}			-	140	ns	
RESET Recovery Time	t _{phel}			1	-	μs	
V _{PP} Setup Time	t _{vpeh}			180	-	ns	
V _{pp} Hold Time	t _{QVVL}			0	-	ns	
Word/Byte Write Time	t _{enqv1}		¥ _{pp} =3:3∨±0.3∨	15	-	μs	
			<b>V</b> _{PP} =5V±10%	8.2	-	μs	
	â		$V_{pp} = 12V \pm 5\%$	6.7	-	μs	
			$V_{pp} = 3.3V \pm 0.3V$	1.5	-	s	
Block Erase Time	t _{ehqv2}		V _{pp} =5V±10%	1.0	-	s	
			V _{PP} =12V±5%	0.8	-	s	
Set Lock-Bit Time		r	$V_{pp}$ =3.3V±0.3V	18	_	μs	
	t EHQV3		V _{PP} =5V±10%	11.2	-	μs	
	r -		V _{PP} =12V±5%	9.7	-	μs	
Clear Block Lock-Bits			$V_{pp} = 3.3V \pm 0.3V$	1.5	-	S	
Time	t _{ehqv4}		$V_{pp} = 5V \pm 10\%$	1.0	-	s	
			$V_{pp} = 12V \pm 5\%$	0.8	-	s	

 $(Vcc=3.3V\pm0.3V, Ta = 0 \text{ to } 60^{\circ}C)$ 

(**************************************						,		
PARAMETER	5	SYMBOL	CONDITION	Vcc=5	V±5%	Vcc=5V	V±10%	Unit
PARAMETER	IEEE	PCMCIA	CONDITION	MIN	MAX	MIN	MAX	Umt
Write Cycle Time	t _{AVAV}	t _{cw}		150	-	150	-	ns
Address Setup Time	t _{AVEL}	t _{su} (A)		20	-	20	-	ns
Write Recovery Time	t _{ehax}	t _{rec} (CE)		20	-	<u>,</u> 20	-	ns
Data Setup Time for CE#	t _{dveh}	t _{su} (D-CEH)		50	-	50	-	ns
Data Hold Time	t _{ehdx}	t _h (D)		20	/40000	20	-	ns
OE# Hold Time from CE#	t _{ehgl}	t _h (OE-CE)		80		80	-	ns
WE# Setup Time for CE#	t _{wleh}	t _{su} (WE-CEH)		100		100	-	ns
Address Setup Time for CE#	t _{aven}	t _{su} (A-CEH)		100	-	100	-	ns
Write Pulse Width	t _{eleh}	t _w (CE)		8Q	₩¥ -	80	-	ns
CE# High to RDY/BSY# going Low	t _{ehrl}				140	+	140	ns
RESET Recovery Time	t _{phel}			1	-	1	-	μs
V _{PP} Setup Time	t _{vpeh}	4		100	-	100	-	ns
V _{pp} Hold Time	t _{QVVL}			0	-	0	-	ns
Word/Byte Write Time			<b>V</b> _{PP} =5 <b>V</b> ±10%	6.5	-	6.5	-	μs
words byte write Time	t _{EHQV1}		<b>V</b> _{PP} =12V±5%	4.8	-	4.8	-	μs
Block Erase Time	t »		V _{PP} =5V±10%	0.9	-	0.9	-	S
Diock Liuse Thile	LEHOW2		V _{PP} =12V±5%	0.3	-	0.3	-	S
Set Lock-Bit Time	t ø		$V_{pp} = 5V \pm 10\%$	9.5	-	9.5	-	μs
Set Lock-Dit Time	LEHOV3		V _{PP} =12V±5%	7.8	-	7.8	-	μs
Clear Block Lock-Bits			V _{pp} =5V±10%	0.9	-	0.9	-	s
Time	t _{ehqv4}		V _{PP} =12V±5%	0.3	-	0.3	-	s

(Vcc=5V±5%, Vcc=5V±10%, Ta=0 to 60°C)



Figure 11. AC Waveforms for Write Operations (CE# Controlled)

Note) While the data signal is in output mode, do not apply an opposite phase input signal.

### 13.3 Power-Up/Power Down

DADAMETED	SYMBOL	NOTES			UDUTO	
PARAMETER	PCMCIA	NOTES	MIN	MAX	UNITS	
CE# Signal Level (0.0V < V _{CC} < 2.0V)	V _i (CE)	1	0	V _{iMAX}	v	
CE# Signal Level $(2.0V < V_{CC} < V_{IH})$		1	V _{CC} 0.1	V _{imax}	v	
CE# Signal Level (V _{IH} < V _{CC} )		1	VIH	Vimax	v	
CE# Setup Time	$t_{su}$ (V _{CC} )		20		ms	
RESET Setup Time	t _{su} (RESET)		20	-	ms	
CE# Recover Time	$t_{rec} (V_{CC})$		1.0		μs	
V _{CC} Rising Time	t _{pr}	2	0.1	300	ms	
V _{CC} Falling Time	t _{pf}	2	3.0	300	ms	
RESET Width	tw (RESET)		10		μs	
RESET Width	th (Hi-Z RESET)				ms	
RESET Width	ts (Hi-Z RESET)		0		ms	

NOTES:

1. V_{iMAX} means Absolute Maximum Voltage for input in the period of  $0.0V < V_{CC} < 2.0$  V, Vi (CE#) is only 0.00V-V_{iMAX}

2. The t_{pr} and t_{pf} are defined as "linear waveforms" in the period of 10% to 90%, or vice-versa. Even if the waveform is not a "liner waveform," its rising and falling time must meet this specification.



### 14. Specification Changes

This datasheet is for ID242 series product overview, and final specifications will be submitted for qualification of the memory card. Please note that contents of this datasheet may be revised without announcement beforehand. Please do NOT finalize a system design with this information.

### **15. Other Precautions**

- Permanent damage occurs if the memory card is stressed beyond Absolute Maximum Ratings. Operation
  beyond the Recommended Operating Conditions is not recommended and extended exposure beyond the
  Recommended Operating Conditions may affect device reliability.
- Writing to the memory card can be prevented by switching on the write protect switch on the end of the memory card.
- Avoid allowing the memory card connectors to come in contact with metals and avoid touching the connectors, as the internal circuits can be damaged by static electricity.
- Avoid storing in direct sunlight, high temperatures (do not place near heaters or radiators), high humidity and dusty areas.
- Avoid subjecting the memory card to strong physical abuse. Dropping, bending, smashing or throwing the card can result in loss of function.
- When the memory card is not being used, return it to its protective case.
- · Do not allow the memory card to come in contact with fire.

### **16. External Diagrams**



Flash Card, Series 2, Intel Compatible, Linear PCMCIA Memory